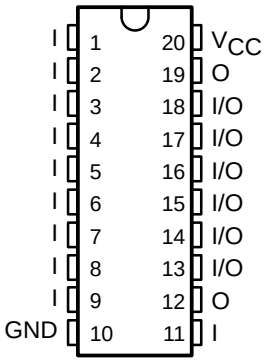
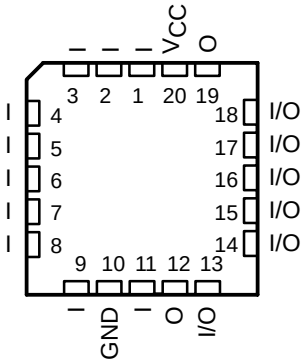
- **High-Performance Operation:**
  Propagation Delay
  C Suffix . . . 25 ns Max
  M Suffix . . . 30 ns Max
- **Functionally Equivalent, but Faster than PAL16L8A, PAL16R4A, PAL16R6A, and PAL16R8A**
- **Power-Up Clear on Registered Devices (All Register Outputs are Set High, but Voltage Levels at the Output Pins Go Low)**
- **Package Options Include Both Plastic and Ceramic Chip Carriers in Addition to Plastic and Ceramic DIPs**
- **Dependable Texas Instruments Quality and Reliability**

DEVICE	I INPUTS	3-STATE O OUTPUTS	REGISTERED Q OUTPUTS	I/O PORTS
PAL16L8	10	2	0	6
PAL16R4	8	0	4 (3-state buffers)	4
PAL16R6	8	0	6 (3-state buffers)	2
PAL16R8	8	0	8 (3-state buffers)	0

TIBPAL16L8'
C SUFFIX . . . J OR N PACKAGE
M SUFFIX . . . J OR W PACKAGE
(TOP VIEW)



TIBPAL16L8'
C SUFFIX . . . FN PACKAGE
M SUFFIX . . . FK PACKAGE
(TOP VIEW)



description

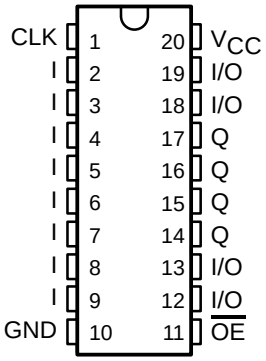
These programmable array logic devices feature high speed and functional equivalency when compared with currently available devices. These IMPACT™ circuits combine the latest Advanced Low-Power Schottky technology with proven titanium-tungsten fuses to provide reliable, high-performance substitutes for conventional TTL logic. Their easy programmability allows for quick design of custom functions and typically results in a more compact circuit board. In addition, chip carriers are available for futher reduction in board space.

The TIBPAL16' C series is characterized from 0°C to 75°C. The TIBPAL16' M series is characterized for operation over the full military temperature range of –55°C to 125°C.

These devices are covered by U.S. Patent 4,410,987.
IMPACT is a trademark of Texas Instruments Incorporated.
PAL is a registered trademark of Advanced Micro Devices Inc.

TIBPAL16R4'
C SUFFIX . . . J OR N PACKAGE
M SUFFIX . . . J OR W PACKAGE

(TOP VIEW)



TIBPAL16R4'
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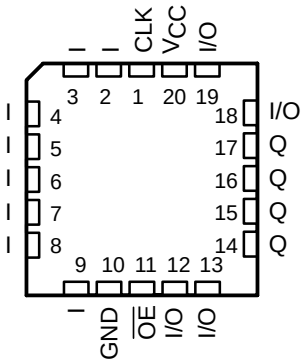
M SUFFIX . . . FK PACKAGE

(TOP VIEW)



TIBPAL16R6'
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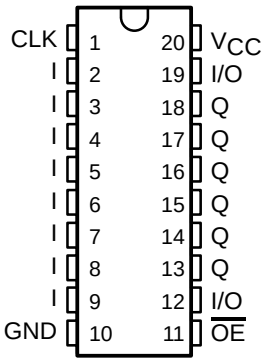
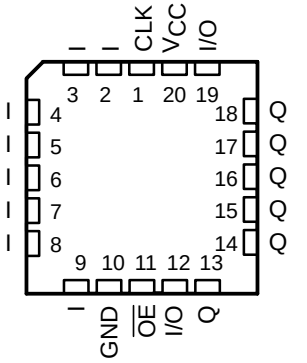
M SUFFIX . . . J OR W PACKAGE

(TOP VIEW)



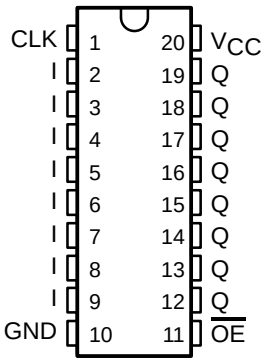
TIBPAL16R6'
C SUFFIX . . . FN PACKAGE
M SUFFIX . . . FK PACKAGE

(TOP VIEW)



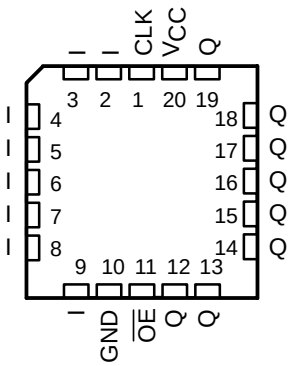
TIBPAL16R8'
C SUFFIX . . . J OR N PACKAGE
M SUFFIX . . . J OR W PACKAGE

(TOP VIEW)



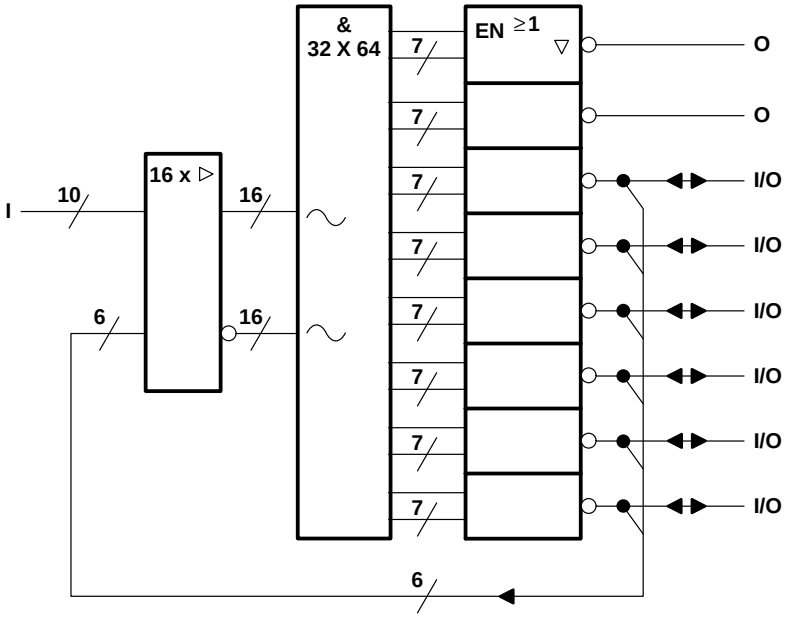
TIBPAL16R8'
C SUFFIX . . . FN PACKAGE
M SUFFIX . . . FK PACKAGE

(TOP VIEW)

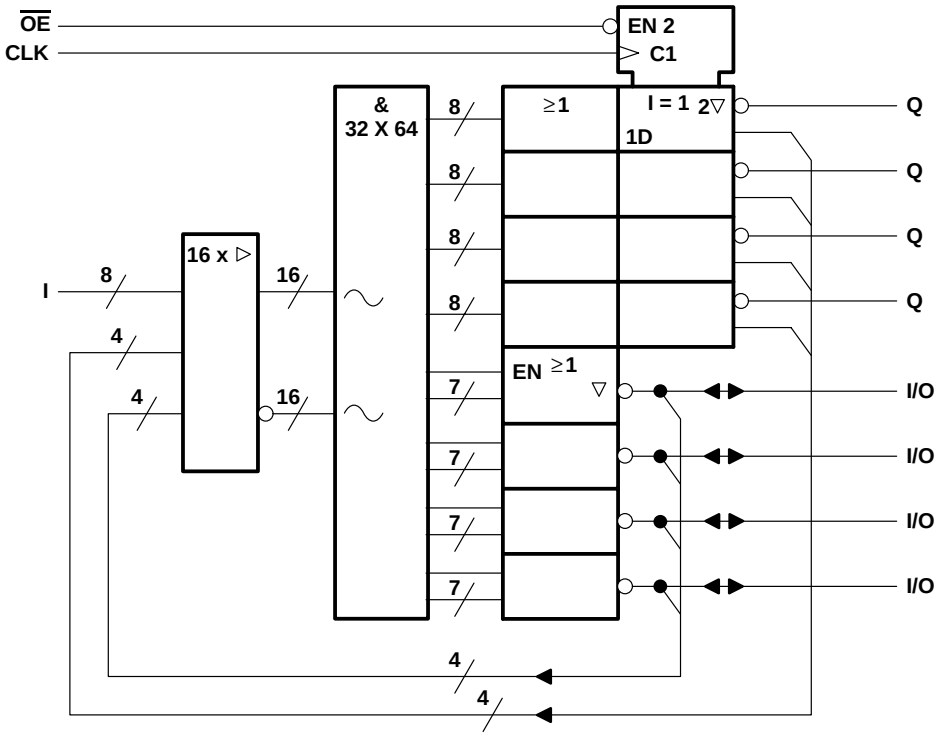


functional block diagrams (positive logic)

TIBPAL16L8'



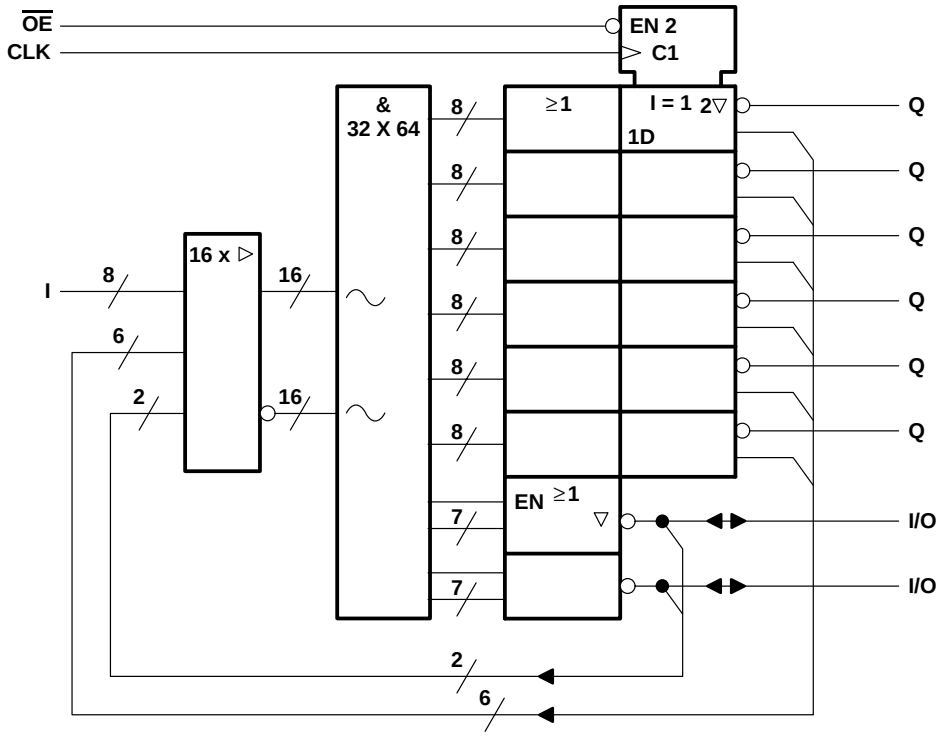
TIBPAL16R4'



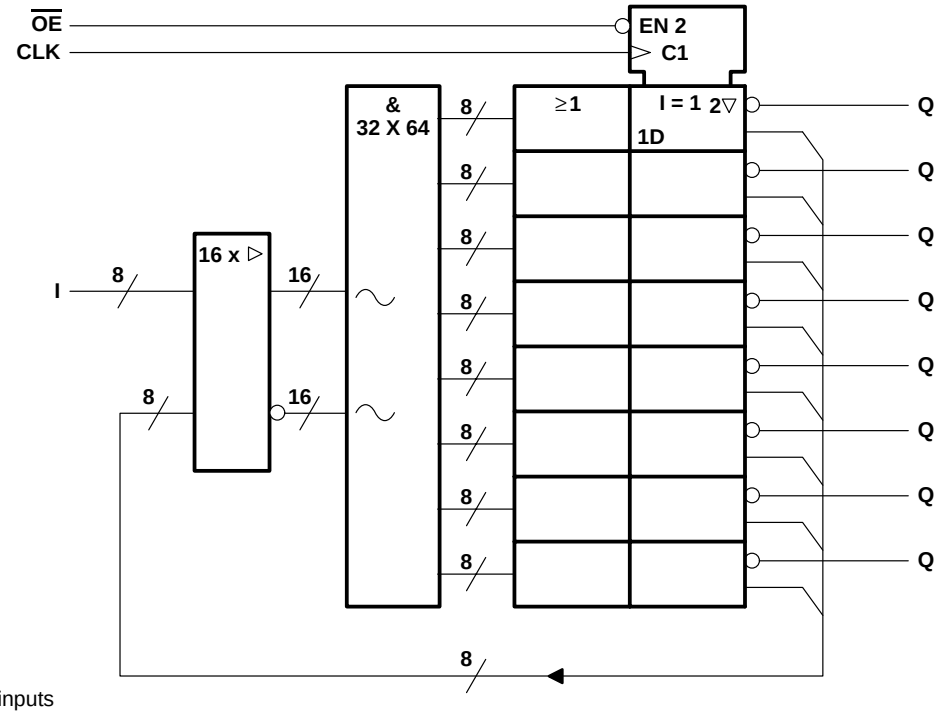
~ denotes fused inputs

functional block diagrams (positive logic)

TIBPAL16R6'

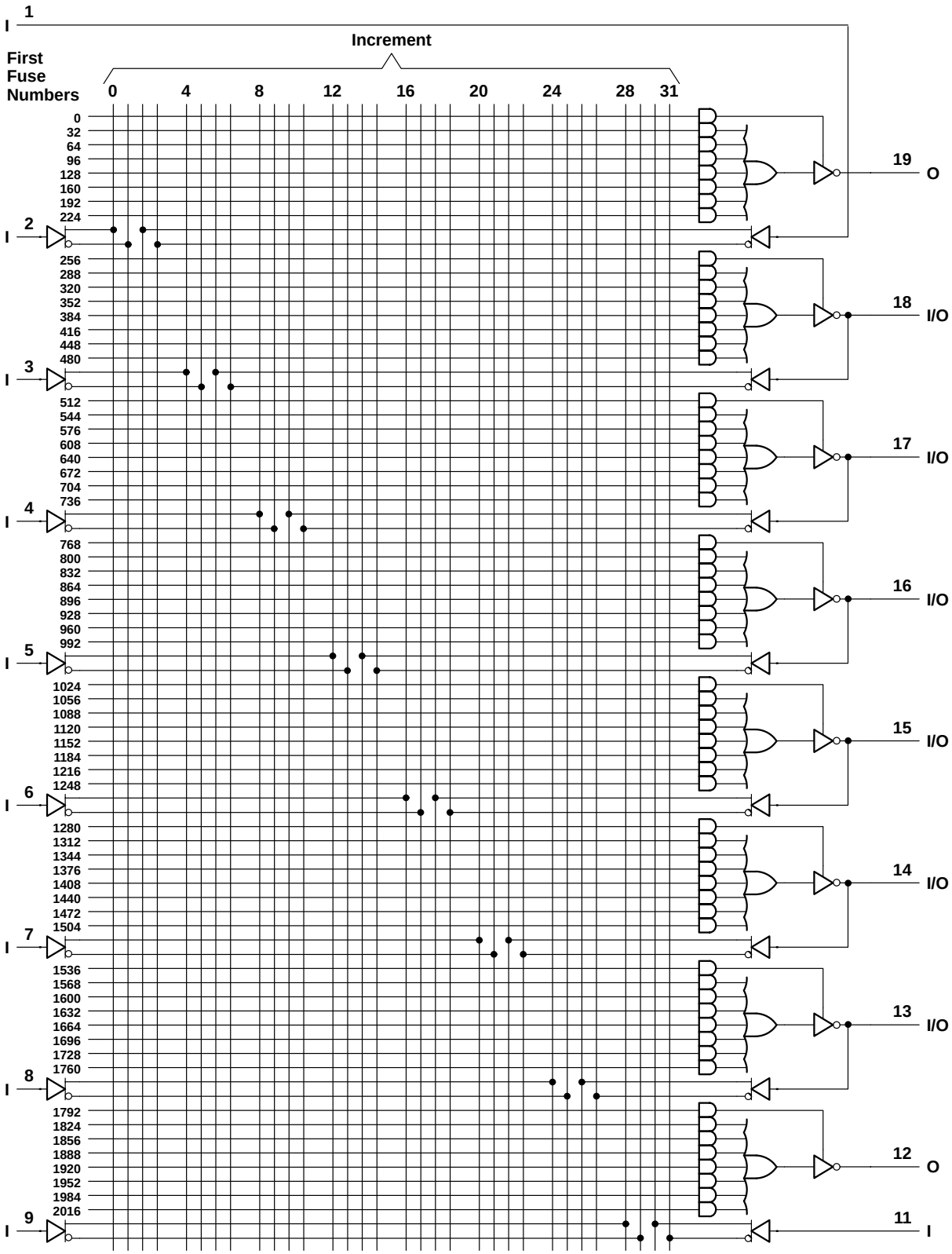


TIBPAL16R8'



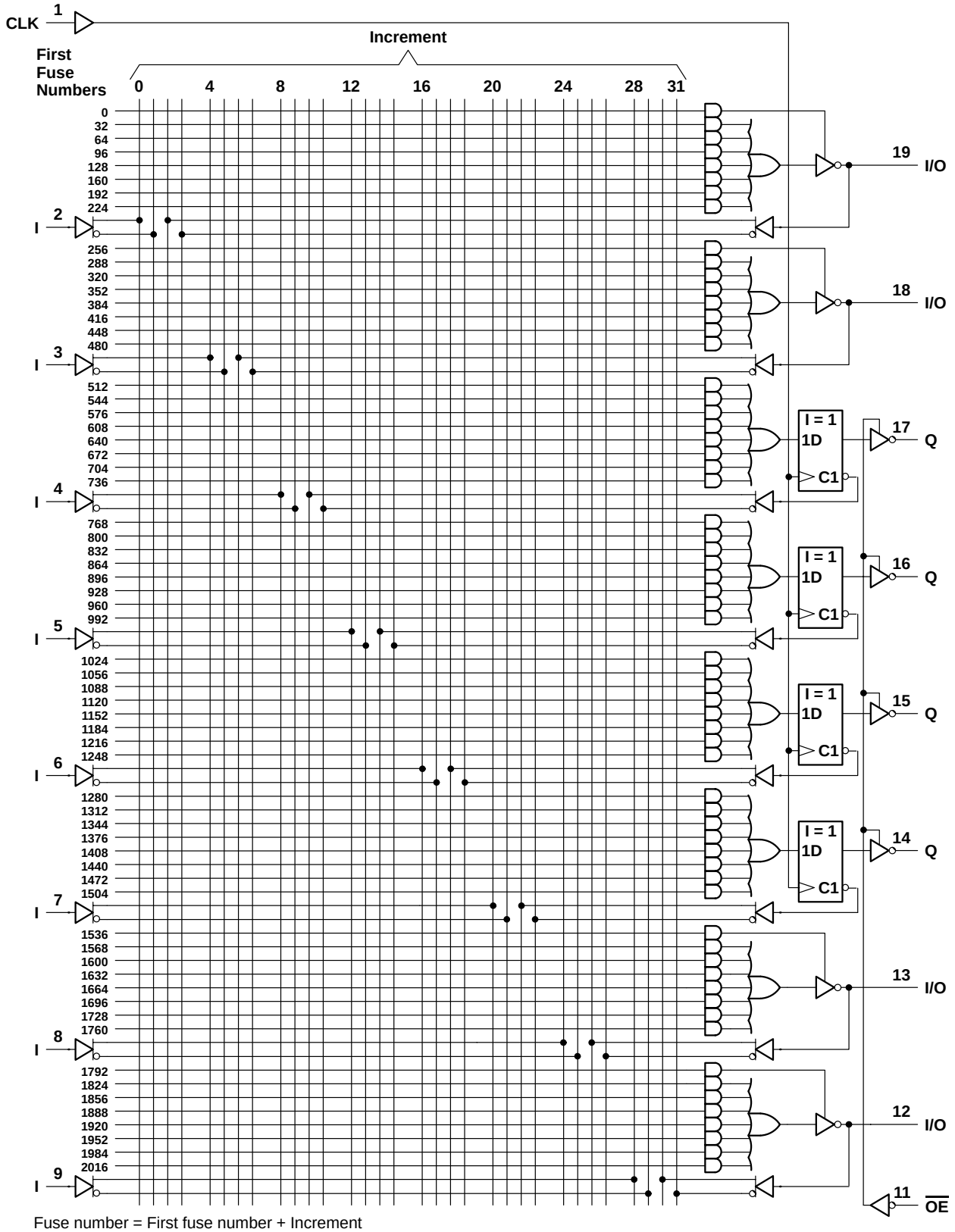
~ denotes fused inputs

logic diagram (positive logic)



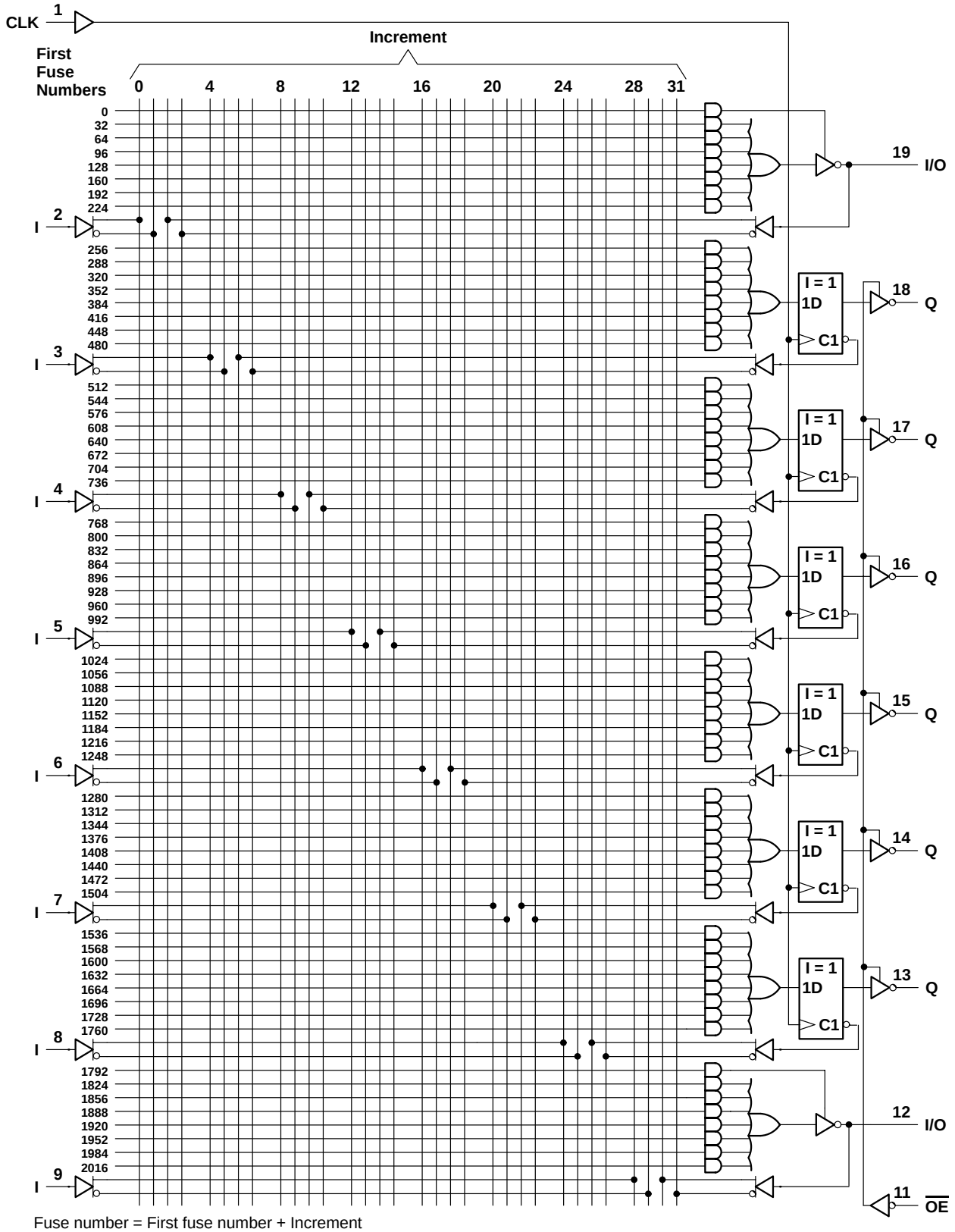
Fuse number = First fuse number + Increment

logic diagram (positive logic)



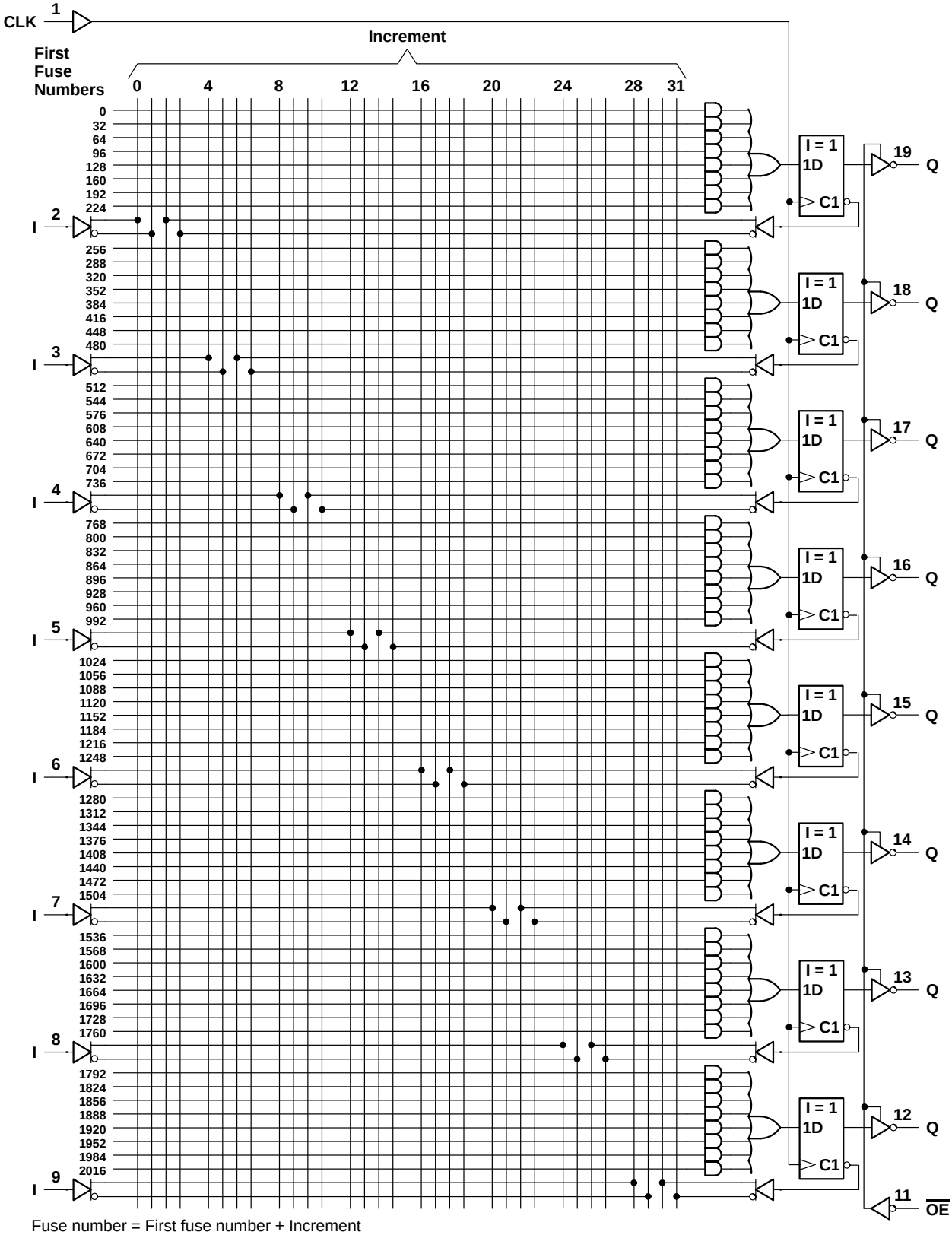
Fuse number = First fuse number + Increment

logic diagram (positive logic)



Fuse number = First fuse number + Increment

logic diagram (positive logic)



Fuse number = First fuse number + Increment

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (see Note 1) . . . . . 7 V
Input voltage (see Note 1) . . . . . 5.5 V
Voltage applied to disabled output (see Note 1) . . . . . 5.5 V
Operating free-air temperature range . . . . . 0°C to 75°C
Storage temperature range . . . . . –65°C to 150°C

NOTE 1: These ratings apply except for programming pins during a programming cycle.

recommended operating conditions

			MIN	NOM	MAX	UNIT
V_{CC}	Supply voltage		4.75	5	5.25	V
V_{IH}	High-level input voltage		2		5.5	V
V_{IL}	Low-level input voltage				0.8	V
I_{OH}	High-level output current				–3.2	mA
I_{OL}	Low-level output current				24	mA
f_{clock}	Clock frequency		0		30	MHz
t_w	Pulse duration, clock (see Note 2)	High	10			ns
		Low	15			
t_{su}	Setup time, input or feedback before clock↑		20			ns
t_h	Hold time, input or feedback after clock↑		0			ns
T_A	Operating free-air temperature		0	25	75	°C

NOTE 2: The total clock period of clock high and clock low must not exceed clock frequency, f_{clock}. The minimum pulse durations specified are only for clock high or low, but not for both simultaneously.

electrical characteristics over recommended operating free-air temperature range

PARAMETER		TEST CONDITIONS			MIN	TYP†	MAX	UNIT
V_{IK}		V_{CC} = 4.75 V,	I_I = –18 mA				–1.5	V
V_{OH}		V_{CC} = 4.75 V,	I_{OH} = –3.2 mA		2.4	3.3		V
V_{OL}		V_{CC} = 4.75 V,	I_{OL} = 24 mA			0.35	0.5	V
I_{OZH}	Outputs	V_{CC} = 5.25 V,	V_O = 2.7 V				20	μA
	I/O ports						100	
I_{OZL}	Outputs	V_{CC} = 5.25 V,	V_O = 0.4 V				–20	μA
	I/O ports						–250	
I_I		V_{CC} = 5.25 V,	V_I = 5.5 V				0.1	mA
I_{IH}		V_{CC} = 5.25 V,	V_I = 2.7 V				20	μA
I_{IL}		V_{CC} = 5.25 V,	V_I = 0.4 V				–0.25	mA
I_O‡		V_{CC} = 5.25 V,	V_O = 2.25 V		–30		–125	mA
I_{CC}		V_{CC} = 5.25 V,	V_I = 0,	Outputs open		75	100	mA

switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITION	MIN	TYP†	MAX	UNIT
f_{max}				30			MHz
t_{pd}	I, I/O	O, I/O			15	25	ns
t_{pd}	CLK↑	Q	R1 = 500 Ω,		10	15	ns
t_{en}	OE↓	Q	R2 = 500 Ω,		15	20	ns
t_{dis}	OE↑	Q	See Figure 3		10	20	ns
t_{en}	I, I/O	O, I/O			14	25	ns
t_{dis}	I, I/O	O, I/O			13	25	ns

† All typical values are at V_{CC} = 5 V, T_A = 25°C.
‡ The output conditions hace been chosen to produce a current that closely approximates one half of the short-circuit output current, I_{OS}.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (see Note 1) . . . . . 7 V
Input voltage (see Note 1) . . . . . 5.5 V
Voltage applied to disabled output (see Note 1) . . . . . 5.5 V
Operating free-air temperature range . . . . . –55°C to 125°C
Storage temperature range . . . . . –65°C to 150°C

NOTE 1: These ratings apply except for programming pins during a programming cycle.

recommended operating conditions

			MIN	NOM	MAX	UNIT
V_{CC}	Supply voltage		4.5	5	5.5	V
V_{IH}	High-level input voltage		2		5.5	V
V_{IL}	Low-level input voltage				0.8	V
I_{OH}	High-level output current				–2	mA
I_{OL}	Low-level output current				12	mA
f_{clock}	Clock frequency		0		25	MHz
t_w	Pulse duration, clock (see Note 2)	High	15			ns
		Low	20			
t_{su}	Setup time, input or feedback before clock↑		25			ns
t_h	Hold time, input or feedback after clock↑		0			ns
T_A	Operating free-air temperature		–55	25	125	°C

NOTE 2: The total clock period of clock high and clock low must not exceed clock frequency, f_{clock}. The minimum pulse durations specified are only for clock high or low, but not for both simultaneously..

electrical characteristics over recommended operating free-air temperature range

PARAMETER		TEST CONDITIONS			MIN	TYP†	MAX	UNIT
V_{IK}		V_{CC} = 4.5 V,	I_I = –18 mA				–1.5	V
V_{OH}		V_{CC} = 4.5 V,	I_{OH} = –2 mA		2.4	3.2		V
V_{OL}		V_{CC} = 4.5 V,	I_{OL} = 12 mA			0.25	0.4	V
I_{OZH}	Outputs	V_{CC} = 5.5 V,	V_O = 2.7 V				20	μA
	I/O ports						100	
I_{OZL}	Outputs	V_{CC} = 5.5 V,	V_O = 0.4 V				–20	μA
	I/O ports						–250	
I_I	Pin 1, 11	V_{CC} = 5.5 V,	V_I = 5.5 V				0.2	mA
	All others						0.1	
I_{IH}	Pin 1, 11	V_{CC} = 5.5 V,	V_I = 2.7 V				50	μA
	I/O ports						100	
	All others						20	
I_{IL}	I/O ports	V_{CC} = 5.5 V,	V_I = 0.4 V				–0.25	mA
	All others						–0.2	
I_{OS}‡		V_{CC} = 5.5 V,	V_O = 0.5 V		–30		–250	mA
I_{CC}		V_{CC} = 5.5 V,	V_I = 0,	Outputs open		75	105	mA

switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITION	MIN	TYP†	MAX	UNIT
f_{max}			R1 = 390 Ω, R2 = 750 Ω, See Figure 4	25			MHz
t_{pd}	I, I/O	O, I/O			15	30	ns
t_{pd}	CLK↑	Q			10	20	ns
t_{en}	OE↓	Q			15	25	ns
t_{dis}	OE↑	Q			10	25	ns
t_{en}	I, I/O	O, I/O			14	30	ns
t_{dis}	I, I/O	O, I/O			13	30	ns

† All typical values are at V_{CC} = 5 V, T_A = 25°C.
‡ Not more than one output should be shorted at a time and the duration of the short circuit should not exceed one second. Set V_O at 0.5 V to avoid test equipment degradation.

programming information

Texas Instruments programmable logic devices can be programmed using widely available software and inexpensive device programmers.

Complete programming specifications, algorithms, and the latest information on hardware, software, and firmware are available upon request. Information on programmers capable of programming Texas Instruments programmable logic is also available, upon request, from the nearest TI field sales office, local authorized TI distributor, or by calling Texas Instruments at (214) 997-5666.

preload procedure for registered outputs (see Figure 1 and Note 3)

The output registers can be preloaded to any desired state during device testing. This permits any state to be tested without having to step through the entire state-machine sequence. Each register is preloaded individually by following the steps given below.

Step 1. With V_{CC} at 5 volts and Pin 1 at V_{IL}, raise Pin 11 to V_{IHH}.
Step 2. Apply either V_{IL} or V_{IH} to the output corresponding to the register to be preloaded.
Step 3. Pulse Pin 1, clocking in preload data.
Step 4. Remove output voltage, then lower Pin 11 to V_{IL}. Preload can be verified by observing the voltage level at the output pin.

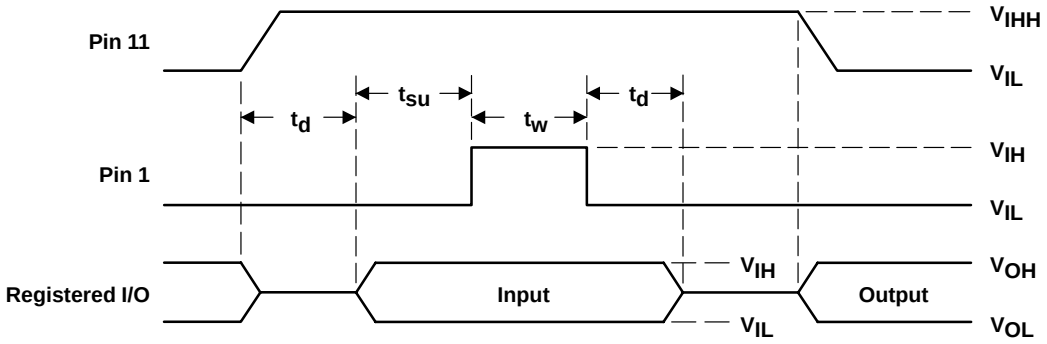
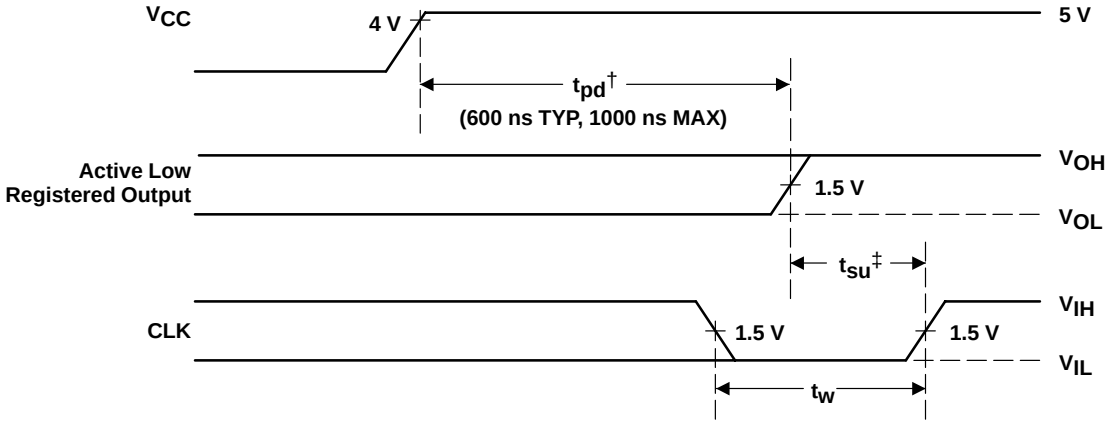


Figure 1. Preload Waveforms

NOTE 3: $t_d = t_{su} = t_h$ = 100 ns to 1000 ns V_{IHH} = 10.25 V to 10.75 v

power-up reset (see Figure 2)

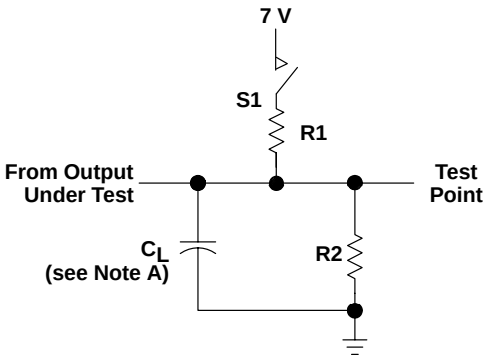
Following power up, all registers are reset to zero. This feature provides extra flexibility to the system designer and is especially valuable in simplifying state-machine initialization. To ensure a valid power-up reset, it is important that the rise of V_{CC} be monotonic. Following power-up reset, a low-to-high clock transition must not occur until all applicable input and feedback setup times are met.



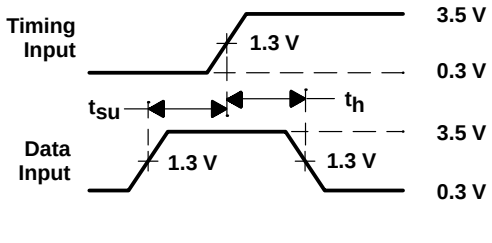
† This is the power-up reset time and applies to registered outputs only. The values shown are from characterization data.
‡ This is the setup time for input or feedback.

Figure 2. Power-Up Reset Waveforms

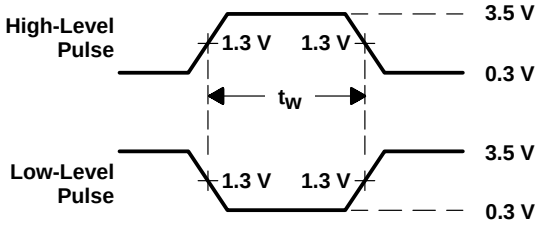
PARAMETER MEASUREMENT INFORMATION



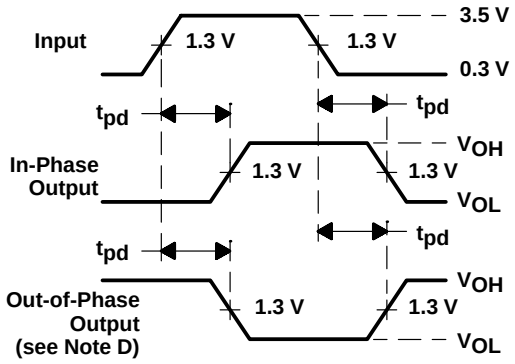
LOAD CIRCUIT FOR 3-STATE OUTPUTS



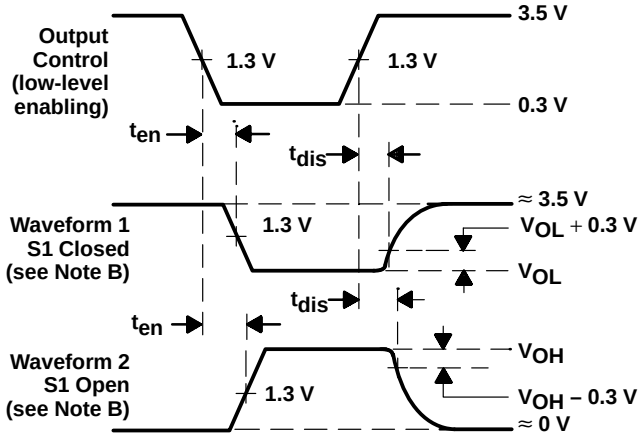
VOLTAGE WAVEFORMS
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS
PULSE DURATIONS



VOLTAGE WAVEFORMS
PROPAGATION DELAY TIMES

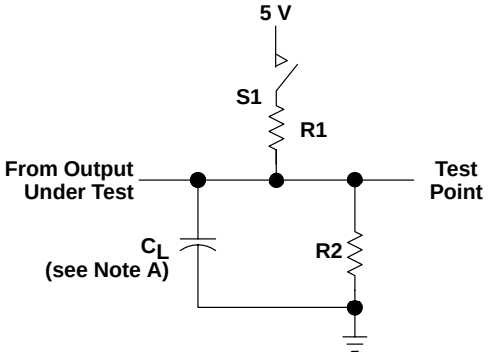


VOLTAGE WAVEFORMS
ENABLE AND DISABLE TIMES, 3-STATE OUTPUTS

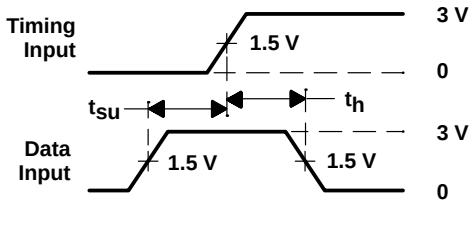
NOTES: A. C_L includes probe and jig capacitance and is 50 pF for t_{pd} and t_{en}, 5 pF for t_{dis}.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses have the following characteristics: PRR ≤ 1 MHz, $t_r = t_f \leq 2$ ns, duty cycle = 50%
D. When measuring propagation delay times of 3-state outputs from low to high, switch S1 is closed. When measuring propagation delay times of 3-state outputs from high to low, switch S1 is open.
E. Equivalent loads may be used for testing.

Figure 3. Load Circuit and Voltage Waveforms

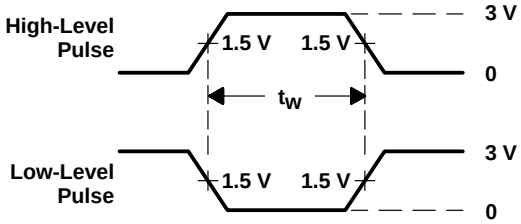
PARAMETER MEASUREMENT INFORMATION



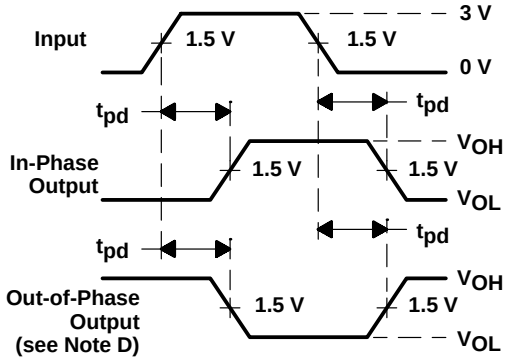
LOAD CIRCUIT FOR 3-STATE OUTPUTS



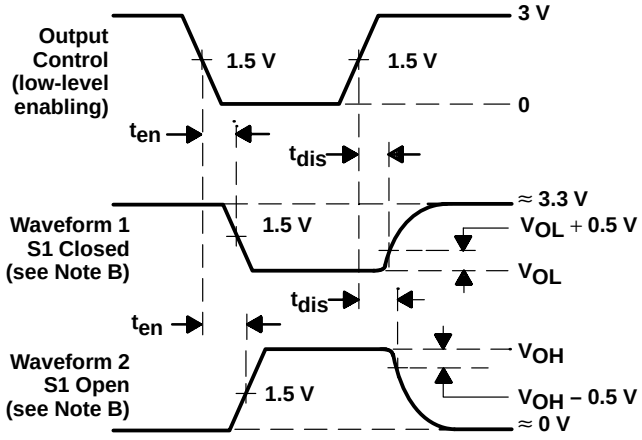
VOLTAGE WAVEFORMS SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS PULSE DURATIONS



VOLTAGE WAVEFORMS PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS ENABLE AND DISABLE TIMES, 3-STATE OUTPUTS

NOTES: A. C_L includes probe and jig capacitance and is 50 pF for t_{pd} and t_{en}, 5 pF for t_{dis}.
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
C. All input pulses have the following characteristics: PRR ≤ 10 MHz, t_r and t_f ≤ 2 ns, duty cycle = 50%
D. When measuring propagation delay times of 3-state outputs, switch S1 is closed.
E. Equivalent loads may be used for testing.

Figure 4. Load Circuit and Voltage Waveforms

IMPORTANT NOTICE

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TI warrants performance of its semiconductor products and related software to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

Certain applications using semiconductor products may involve potential risks of death, personal injury, or severe property or environmental damage ("Critical Applications").

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